Flexible all-inorganic photoconductor detectors based on perovskite/hole-conducting layer heterostructures

Zhi Yang, a,* Jinjuan Dou, a Minqiang Wang, a,* Junjie Li, a Jin Huang, a Jinyou Shao b

a Electronic Materials Research Laboratory (EMRL), Key Laboratory of Education Ministry; International Center for Dielectric Research (ICDR), Shaanxi Engineering Research Center of Advanced Energy Materials and Devices, School of Electronic and Information Engineering, Xi’an Jiaotong University, Xi’an 710049, China.

b State Key Laboratory of Manufacturing Systems Engineering, Xi’an Jiaotong University, Xi’an 710049, China.

Corresponding Author:

*E-mail: yangzhi029@xjtu.edu.cn  mqwang@xjtu.edu.cn.

Fig. S1 TEM images of CsPbBr₃ (a) NCs, (b) NSs
Fig. S2 Optical spectra of CsPbBr₃ NCs and NSs

Fig. S3 (a) Microphotograph and (b) SEM image of single chip
Fig. S4 AFM images of (a) CuSCN and (b) NiO films. It is difficult to distinguish the crystal size of CuSCN film, and obvious grain is observed for NiO film because it is obtained by spin-coating NiO nanocrystal solution. Their corresponding average roughness are 1.5 nm and 6 nm, indicating higher roughness of NiO film.